

Date Searched: 12/22/2005

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 (measur\$6 or test\$3 or prob\$3) near5 (terminal or pad or "i/o" or "i/os" or input or output or (input adj output))

L2 ((top or topmost or uppermost or upper or highest) near5 layer) same 1

L3 (dr or (design near3 (rule or constrain\$4))) same 1

L4 (layout or floorplan\$4 or placement or arrang\$6 or laying or laid or plac\$3 or (floor adj plan \$4)) same 1

L5 2 and 3 and 4

Results: 11 hits

L6 (dr or (design near3 (rule or constrain\$4)) or (minimum adj2 (space or spacing or distance or pitch or width)) or non-overlap\$4 or ("not" adj2 overlap\$4))

L7 6 same 1

L8 (connect\$4 or interconnect\$4 or wire or wiring or route or routing) same 1

L9 6 and 4 and 8

Results: 414 hits

L10 716/1-18.ccls. and 9

Results: 25 hits

L11 (measur\$6 or test\$3 or prob\$3 or scan\$4) near5 (terminal or pad or port or pin)

L12 6 same 11

L13 (connect\$4 or interconnect\$4 or wire or wiring or route or routing) same 11

L14 (layout or floorplan\$4 or placement or arrang\$6 or laying or laid or plac\$3 or (floor adj plan \$4)) same 11

L15 12 and 13 and 14

Results: 355 hits

L16 15 and 716/1-18.ccls.

Results: 41 hits

L17 ((measur\$6 or test\$3 or prob\$3 or scan\$4) near5 (terminal or pad or port or pin)) or tap

L18 (dr or (design near3 (rule or constrain\$4)) or ((minimum or maximum or optim\$4) adj2 (space or spacing or distance or pitch or width or number)) or non-overlap\$4 or ("not" adj2 overlap \$4))

L19 multilayer or multi-layer or layers!

L20 ((top or topmost or uppermost or upper or highest) near5 layer)

L21 17 same 18

L22 17 same 20

L23 (connect\$4 or interconnect\$4 or wire or wiring or route or routing) same 17

L24 (layout or floorplan\$4 or placement or arrang\$6 or laying or laid or plac\$3 or (floor adj plan \$4))

same 17

L25 19 and 21 and 22 and 23 and 24

Results: 31 hits

L26 ("i/o" near5 cell) same (placement or layout or floorplan\$4 or floor-plan\$4)

L27 11 and 26 and 716/1-18.ccls.

Results: 34 hits

US 6823501 B1

USPAT Dahl; Peter 716/9

US 5981302 A

USPAT Alswede; Frank et al. 438/15

US 5917197 A

USPAT Alswede; Frank et al. 257/48

US 20050188340 A1

US-PGPUB Takeoka, Sadami 716/13

US 20010021990 A1

US-PGPUB Takeoka, Sadami et al. 716/1

US 6631504 B2

USPAT Dervisoglu; Bulent et al. 716/4

US 6539520 B1

USPAT Tiong; Spencer Hao et al. 716/3

US 20030082836 A1

US-PGPUB Fetterman, H. Scott et al. 438/14

US 6937047 B2	USPAT Tran; Tu-Anh et al.	324/763
US 20020089345 A1	US-PGPUB Doong, Yih-Yuh et al.	324/765
US 6680484 B1	USPAT Young; Bradley Scott	257/48
US 6577149 B2	USPAT Doong; Yih-Yuh et al.	324/765
US 5640327 A	USPAT Ting; Benjamin S.	716/7
US 5155065 A	USPAT Schweiss; Helmut	438/599
US 20020166100 A1	US-PGPUB Meding, Uwe	716/5
US 6539536 B1	USPAT Singh; Harbinder et al.	716/18
US 6460169 B1	USPAT Camporese; Peter J. et al.	716/10
US 6348805 B1	USPAT Jackson; William E. et al.	324/758
US 20020105049 A1	US-PGPUB Barney, Clive Alva et al.	257/511
US 6747445 B2	USPAT Fetterman; H. Scott et al.	324/71.1
US 20020004929 A1	US-PGPUB Osaki, Seiko et al.	716/10
US 20010039642 A1	US-PGPUB Anzai, Takahiro	716/10
US 6941536 B2	USPAT Muranaka; Masaya	716/14
US 6823502 B2	USPAT Wingren; Matthew Scott et al.	716/9
US 6564362 B2	USPAT Osaki; Seiko et al.	716/10
US 6516446 B2	USPAT Anzai; Takahiro	716/1
US 5552333 A	USPAT Cheung; Gary H. et al.	438/129

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 (measur\$6 or test\$3 or prob\$3 or scan\$4) near5 (terminal or pad or port or pin)  
 L2 (dr or (design near3 (rule or constrain\$4)) or (minimum adj2 (space or spacing or distance or pitch or width)) or non-overlap\$4 or ("not" adj2 overlap\$4))  
 L3 (connect\$4 or interconnect\$4 or wire or wiring or route or routing) near15 1  
 L4 (layout or floorplan\$4 or placement or arrang\$6 or laying or laid or plac\$3 or (floor adj plan \$4)) near15 1  
 L5 2 and 3 and 4  
 Results: 12 hits

L6 ("i/o" near5 cell) same (placement or layout or floorplan\$4 or floor-plan\$4)  
 L7 (measur\$6 or test\$3 or prob\$3 or scan\$4) near5 (terminal or pad or port or pin)  
 L8 6 and 7  
 Results: 2 hits

NN9005325	IBM_TDB
JP 09178774 A	JPO BAYER, THOMAS et al.

Database Searched: IEE/IEEE XPlore

Terms Searched: ((measur\* or test\* or prob\* or scan\*) <near/5> (terminal or pad or port or pin)) and ((dr or (design <near/3> (rule or constrain\$4)) or (minimum <near/2> (space or spacing or distance or pitch or width)) or non-overlap\* or ("not" <near/2> overlap\*))) and (connect\* or interconnect\* or wire or wiring or route or routing) and (layout or floorplan\* or placement or arrang\* or laying or laid or plac\* or (floor <near/1> plan\*))

Results: Your search matched 1 of 1286976 documents.

Terms Searched: ((measur\* or test\* or prob\* or scan\*) <near/5> (terminal or pad or port or pin)) and (connect\* or interconnect\* or wire or wiring or route or routing) and (layout or floorplan\* or placement or arrang\* or laying or laid or plac\* or (floor <near/1> plan\*)) and ("i/o" <near/5> cell)

Results: Your search matched 0 documents

Terms Searched: ((measur\* or test\* or prob\* or scan\*) <near/5> (terminal or pad or port or pin)) and ("i/o" <near/5> cell)

Results: Your search matched **5** of **1286976** documents